

Potential-induced degradation of the shunting type: on the origin of sodium in shunt paths

Robbe Breugelmans^{1,3,4}, Jorne Carolus^{1,3,4}, Arvid van der Heide^{2,4}, Eszter Voroshazi^{2,4}, Michaël Daenen^{1,3,4}

¹Institute for Materials Research (IMO), Hasselt University, Wetenschapspark 1, 3590 Diepenbeek, Belgium

²imec, Kapeldreef 75, 3001 Leuven, Belgium

³IMOMEc, imec, Wetenschapspark 1, 3590 Diepenbeek, Belgium

⁴EnergyVille 2, Thor Park 8320, 3600 Genk, Belgium

1. Introduction

Potential-induced degradation rapidly and significantly affects the photovoltaic (PV) module's performance due to a high potential difference across the PV cell and the

grounded module's frame.[1] PID has various types where PID of the shunting type (PID-s) is common within silicon PV cells.[2] Extensive research already points towards sodium (Na) ions as the root cause of the efficiency degradation under PID-s.[3] However, the origin of the Na ions is still under debate. Some publications state that the soda-lime glass (SLG) cover of the PV module is the main source of the Na ions. In contrast, others have proven to degrade solar cells in the absence of an encapsulation material and front cover glass. [3-6]

With this work, we try to find an answer to the current debate and thus find the source of the Na ions causing PID-s.

2. Experimental

- 10 samples: 5xA and 5xB
- Foil method
- Climate chamber:
 - 60°C
 - < 60% relative humidity
- 315 hours of HV stress

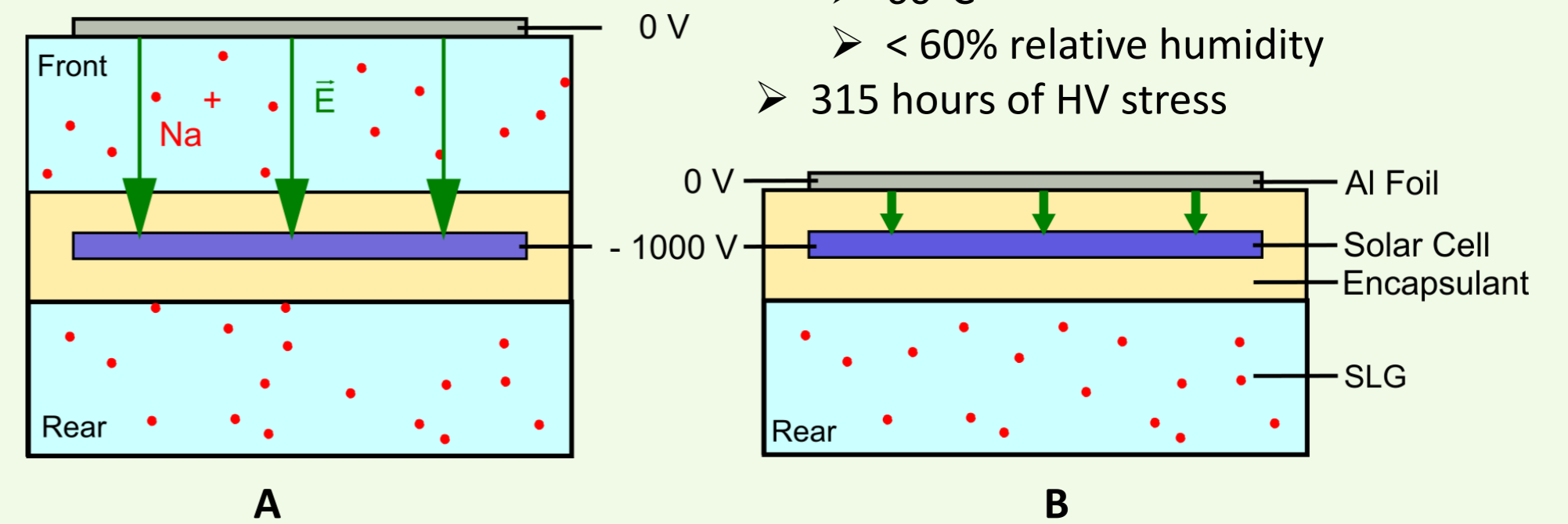


Figure 2: Configuration A laminate using SLG front cover, and configuration B without SLG front cover

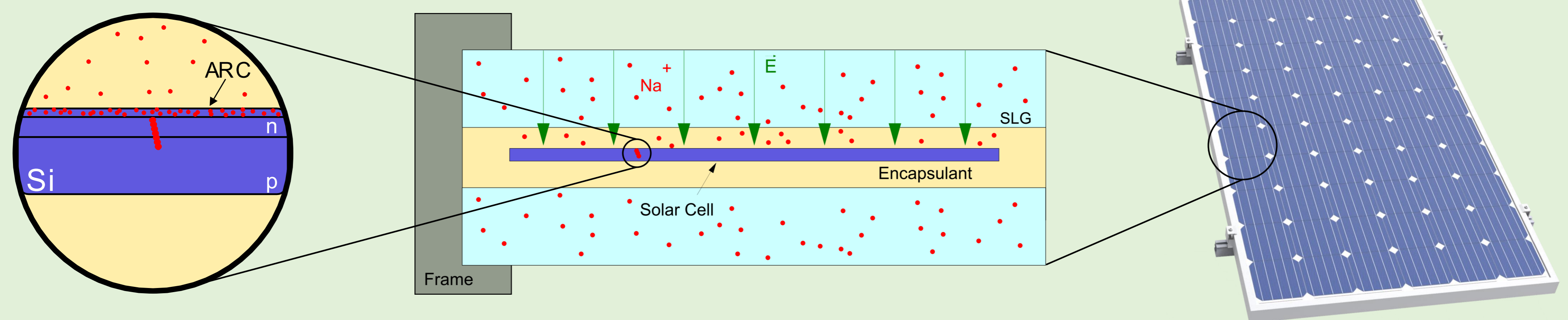


Figure 1: Graphical abstract of PID-s

3. Results

Five identical multicrystalline glass/glass configured mini-modules, together with five laminates with the absence of an SLG front cover underwent 315 hours of high-voltage stress under controlled environmental

conditions. Figure 3 illustrates the light IV curves of the intermediately measured configuration A and B laminates. It is noticeable that the area beneath the IV curve of the configuration A laminate is significantly affected with increasing stressing time. The decrease in power is mainly attributed to a change of the IV curve's slope near I_{SC} . Hence, this means that the laminate's shunt resistance is affected, and the module is experiencing PID of the shunting type. This is in great contrast to the configuration B laminate where no significant changes in I_{SC} , V_{OC} , or power are noticeable.

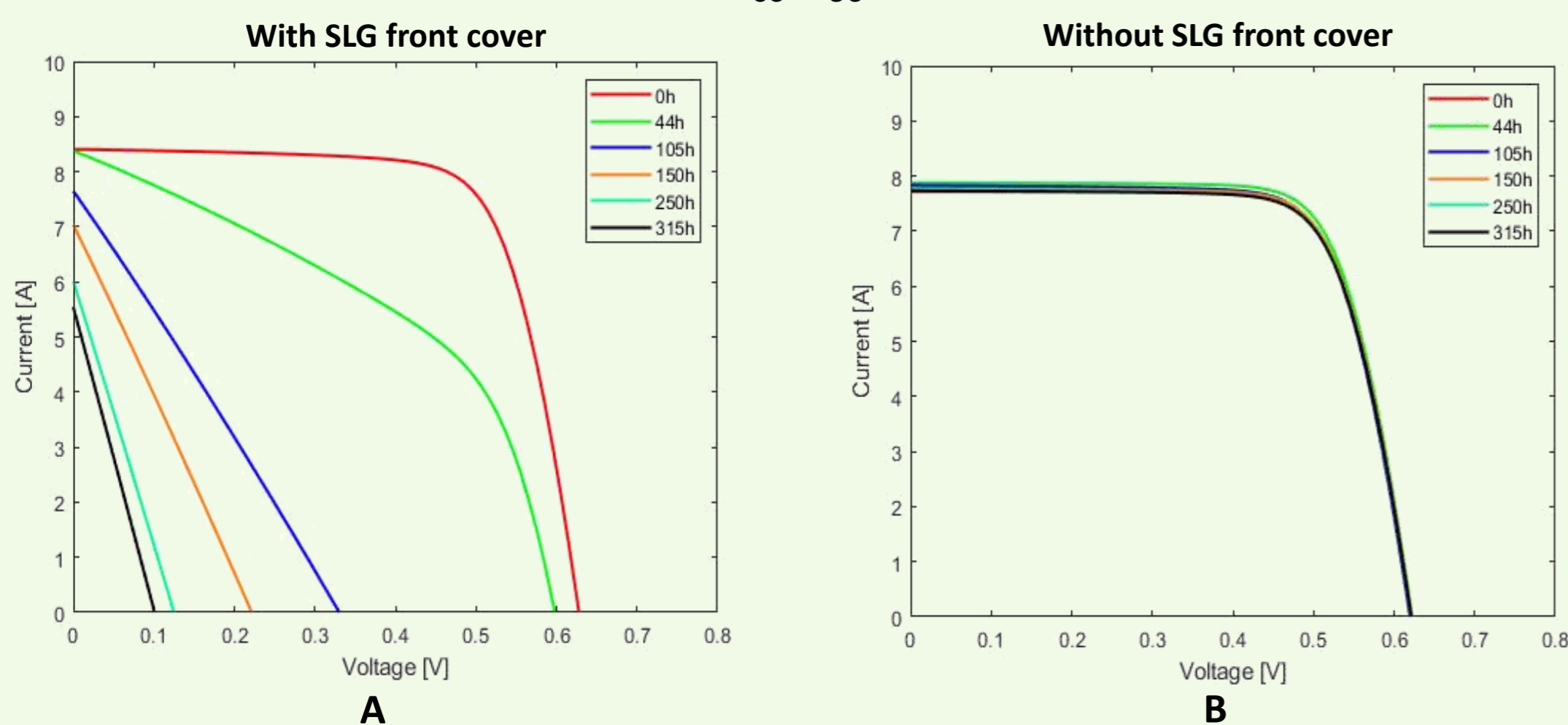


Figure 3: Light IV of configuration A and B laminates

4. Conclusion

Extensive research already identified sodium ions as the root cause of the efficiency degradation under PID-s.[3] Although the origin of these ions is still under debate.

From the results acquired with this research, it can be concluded that the SLG front cover behaves as the main supplier for the sodium ions, which are the dominant factor within the PID-s mechanism. This conclusion can be made since only the cells containing an SLG front cover degrade, in contrast to the laminates without SLG front cover.

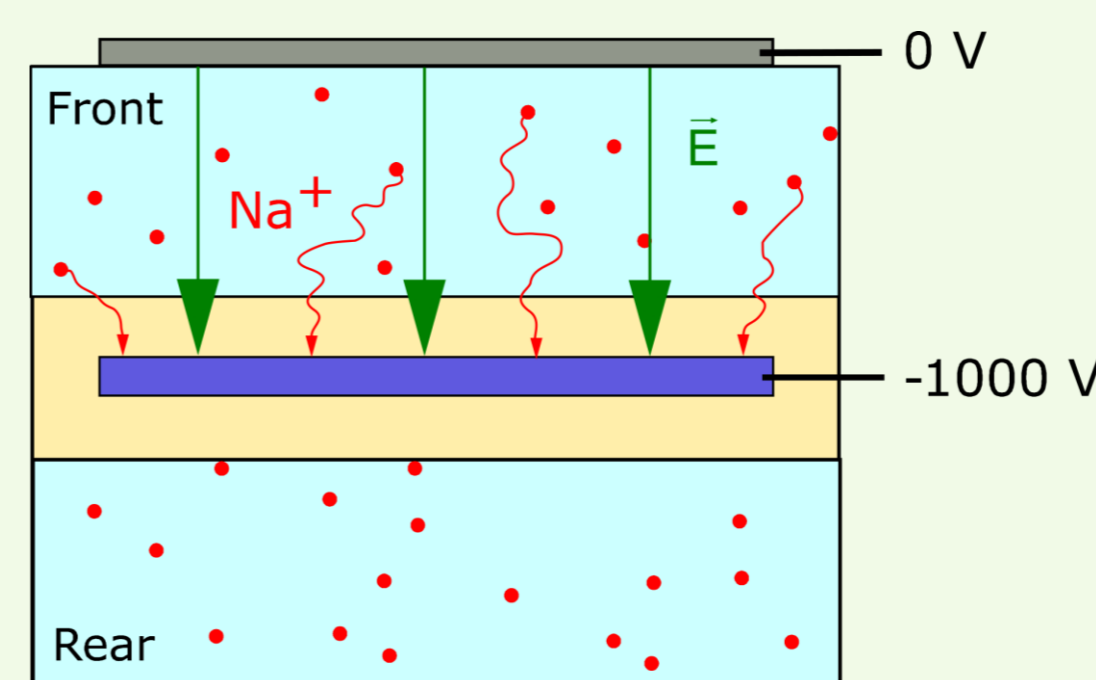


Figure 4: Sodium ion migration from the SLG front cover towards the solar cell under influence of an electric field

Acknowledgement

This study has received funding from the project RollingSolar, financed by the cross-border collaboration program Interreg V Flanders-Netherlands with financial support of the European Funds for Regional Development.

References

- [1] S. Pingel, O. Frank, M. Winkler, S. Oaryan, T. Geipel, H. Hoehne, and J. Berghold, "Potential induced degradation of solar cells and panels," in *Conference Record of the IEEE Photovoltaic Specialists Conference*, 2010, pp. 2817–2822, doi: 10.1109/PVSC.2010.5616823.
- [2] V. Naumann, D. Lausch, A. Hähnel, J. Bauer, O. Breitenstein, A. Graff, M. Werner, S. Swatek, S. Großer, J. Bagdahn, and C. Hagendorf, "Explanation of potential-induced degradation of the shunting type by Na decoration of stacking faults in Si solar cells," *Sol. Energy Mater. Sol. Cells*, 2014, doi: 10.1016/j.solmat.2013.06.015.
- [3] W. Luo, Y. S. Khoo, P. Hacke, V. Naumann, D. Lausch, S. P. Harvey, J. P. Singh, J. Chai, Y. Wang, A. G. Aberle, and S. Ramakrishna, "Potential-induced degradation in photovoltaic modules: A critical review," *Energy and Environmental Science*, vol. 10, no. 1. Royal Society of Chemistry, pp. 43–68, Jan. 01, 2017, doi: 10.1039/c6ee02271e.
- [4] P. Hacke, R. Smith, K. Terwilliger, S. Glick, D. Jordan, S. Johnston, M. Kempe, and S. Kurtz, "Acceleration factor determination for potential-induced degradation in crystalline silicon PV modules," 2013, doi: 10.1109/IRPS.2013.6532009.
- [5] V. Naumann, D. Lausch, and C. Hagendorf, "Sodium Decoration of PID-s Crystal Defects after Corona Induced Degradation of Bare Silicon Solar Cells," in *Energy Procedia*, 2015, vol. 77, pp. 397–401, doi: 10.1016/j.egypro.2015.07.055.
- [6] S. Jonai and A. Masuda, "Origin of Na causing potential-induced degradation for p-type crystalline Si photovoltaic modules," *AIP Adv.*, vol. 8, no. 11, Nov. 2018, doi: 10.1063/1.5040516.